

APPENDIX C CALIBRATION DOCUMENTS

1. SN: 3563 Probe Calibration Certificate
2. SN: 1008 Dipole Calibration Certificate



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Calibration Laboratory of
Schmid & Partner
Engineering AG
 Zeughausstrasse 43, 8004 Zurich, Switzerland



S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
S Servizio svizzero di taratura
S Swiss Calibration Service

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 Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 108**

Client **EMC Technologies**

Certificate No: **EX3-3563_Jul10**

CALIBRATION CERTIFICATE

Object **EX3DV4 - SN:3563**

Calibration procedure(s) **QA CAL-01.v6, QA CAL-14.v3, QA CAL-23.v3 and QA CAL-25.v2**
Calibration procedure for dosimetric E-field probes

Calibration date: **July 15, 2010**

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
 The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	1-Apr-10 (No. 217-01136)	Apr-11
Power sensor E4412A	MY41495277	1-Apr-10 (No. 217-01136)	Apr-11
Power sensor E4412A	MY41498087	1-Apr-10 (No. 217-01136)	Apr-11
Reference 3 dB Attenuator	SN: S5054 (3c)	30-Mar-10 (No. 217-01159)	Mar-11
Reference 20 dB Attenuator	SN: S5086 (20b)	30-Mar-10 (No. 217-01161)	Mar-11
Reference 30 dB Attenuator	SN: S5129 (30b)	30-Mar-10 (No. 217-01160)	Mar-11
Reference Probe ES3DV2	SN: 3013	30-Dec-09 (No. ES3-3013_Dec09)	Dec-10
DAE4	SN: 660	20-Apr-10 (No. DAE4-660_Apr10)	Apr-11
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (in house check Oct-09)	In house check: Oct-11
Network Analyzer HP 8753E	US37390585	18-Oct-01 (in house check Oct-09)	In house check: Oct10

Calibrated by:	Name Katja Pokovic	Function Technical Manager	Signature 
Approved by:	Name Niels Kuster	Function Quality Manager	

Issued: July 15, 2010

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Certificate No: EX3-3563_Jul10

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Glossary:

TSL	tissue simulating liquid
NORM _{x,y,z}	sensitivity in free space
ConvF	sensitivity in TSL / NORM _{x,y,z}
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A, B, C	modulation dependent linearization parameters
Polarization ϕ	ϕ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis

Calibration is Performed According to the Following Standards:

- IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- NORM_{x,y,z}**: Assessed for E-field polarization $\vartheta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). NORM_{x,y,z} are only intermediate values, i.e., the uncertainties of NORM_{x,y,z} does not effect the E^2 -field uncertainty inside TSL (see below ConvF).
- NORM(f)_{x,y,z}** = NORM_{x,y,z} * frequency_response (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of ConvF.
- DCP_{x,y,z}**: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- A_{x,y,z}; B_{x,y,z}; C_{x,y,z}; VR_{x,y,z}; A, B, C** are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters**: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM_{x,y,z} * ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- Spherical isotropy (3D deviation from isotropy)**: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset**: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.



Accreditation No. 5292

EX3DV4 SN:3563

July 15, 2010

Probe EX3DV4

SN:3563

Manufactured:	February 14, 2005
Last calibrated:	July 16, 2009
Recalibrated:	July 15, 2010

Calibrated for DASY/EASY Systems

(Note: non-compatible with DASY2 system!)



EX3DV4 SN:3563

July 15, 2010

DASY/EASY - Parameters of Probe: EX3DV4 SN:3563**Basic Calibration Parameters**

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm ($\mu V/(V/m)^2$) ^A	0.39	0.38	0.48	± 10.1%
DCP (mV) ^B	85.3	89.8	85.7	

Modulation Calibration Parameters

UID	Communication System Name	PAR		A dB	B dBuV	C	VR mV	Unc ^E (k=2)
10000	CW	0.00	X	0.00	0.00	1.00	300	± 1.5%
			Y	0.00	0.00	1.00	300	
			Z	0.00	0.00	1.00	300	

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of NormX,Y,Z do not affect the E²-field uncertainty inside TSL (see Pages 5 and 6).

^B Numerical linearization parameter: uncertainty not required.

^E Uncertainty is determined using the maximum deviation from linear response applying recatangular distribution and is expressed for the square of the field value.



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EX3DV4 SN:3563

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DASY/EASY - Parameters of Probe: EX3DV4 SN:3563**Calibration Parameter Determined in Head Tissue Simulating Media**

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
900	± 50 / ± 100	41.5 ± 5%	0.97 ± 5%	8.31	8.31	8.31	0.49	0.70 ± 11.0%
1810	± 50 / ± 100	40.0 ± 5%	1.40 ± 5%	7.24	7.24	7.24	0.50	0.69 ± 11.0%
1950	± 50 / ± 100	40.0 ± 5%	1.40 ± 5%	6.93	6.93	6.93	0.57	0.62 ± 11.0%
2450	± 50 / ± 100	39.2 ± 5%	1.80 ± 5%	6.53	6.53	6.53	0.34	0.81 ± 11.0%
3500	± 50 / ± 100	37.9 ± 5%	2.91 ± 5%	6.28	6.28	6.28	0.30	1.32 ± 13.1%
5200	± 50 / ± 100	36.0 ± 5%	4.66 ± 5%	4.26	4.26	4.26	0.38	1.80 ± 13.1%
5600	± 50 / ± 100	35.5 ± 5%	5.07 ± 5%	3.82	3.82	3.82	0.38	1.80 ± 13.1%
5800	± 50 / ± 100	35.3 ± 5%	5.27 ± 5%	3.70	3.70	3.70	0.43	1.80 ± 13.1%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.



EX3DV4 SN:3563

July 15, 2010

DASY/EASY - Parameters of Probe: EX3DV4 SN:3563**Calibration Parameter Determined in Body Tissue Simulating Media**

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
900	± 50 / ± 100	55.0 ± 5%	1.05 ± 5%	8.51	8.51	8.51	0.53	0.71 ± 11.0%
1810	± 50 / ± 100	53.3 ± 5%	1.52 ± 5%	7.04	7.04	7.04	0.55	0.69 ± 11.0%
1950	± 50 / ± 100	53.3 ± 5%	1.52 ± 5%	7.13	7.13	7.13	0.47	0.73 ± 11.0%
2450	± 50 / ± 100	52.7 ± 5%	1.95 ± 5%	6.72	6.72	6.72	0.23	1.00 ± 11.0%
3500	± 50 / ± 100	51.3 ± 5%	3.31 ± 5%	5.62	5.62	5.62	0.20	2.26 ± 13.1%
5200	± 50 / ± 100	49.0 ± 5%	5.30 ± 5%	3.78	3.78	3.78	0.45	1.90 ± 13.1%
5600	± 50 / ± 100	48.5 ± 5%	5.77 ± 5%	3.20	3.20	3.20	0.50	1.90 ± 13.1%
5800	± 50 / ± 100	48.2 ± 5%	6.00 ± 5%	3.25	3.25	3.25	0.60	1.90 ± 13.1%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

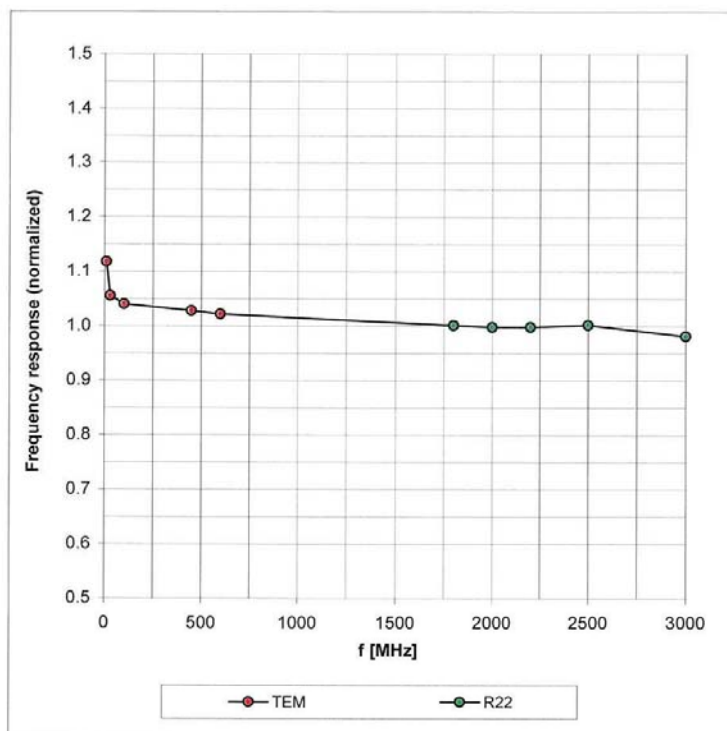


EX3DV4 SN:3563

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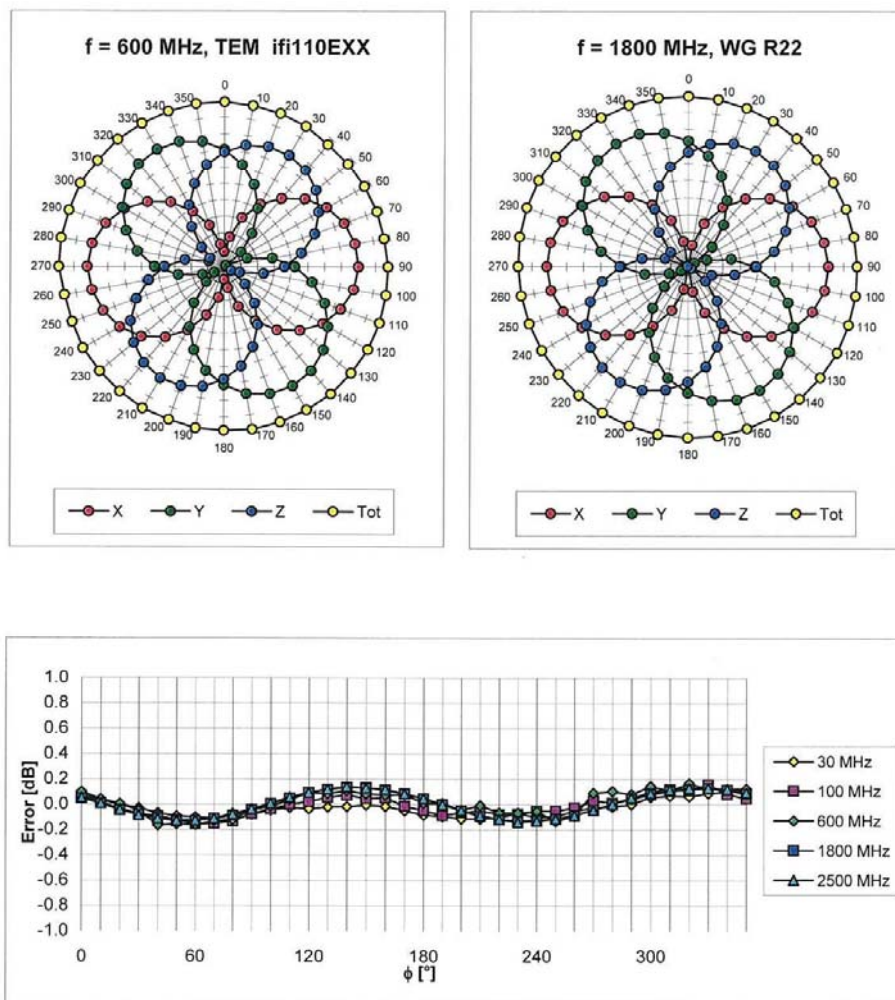
Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)

Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ ($k=2$)

EX3DV4 SN:3563

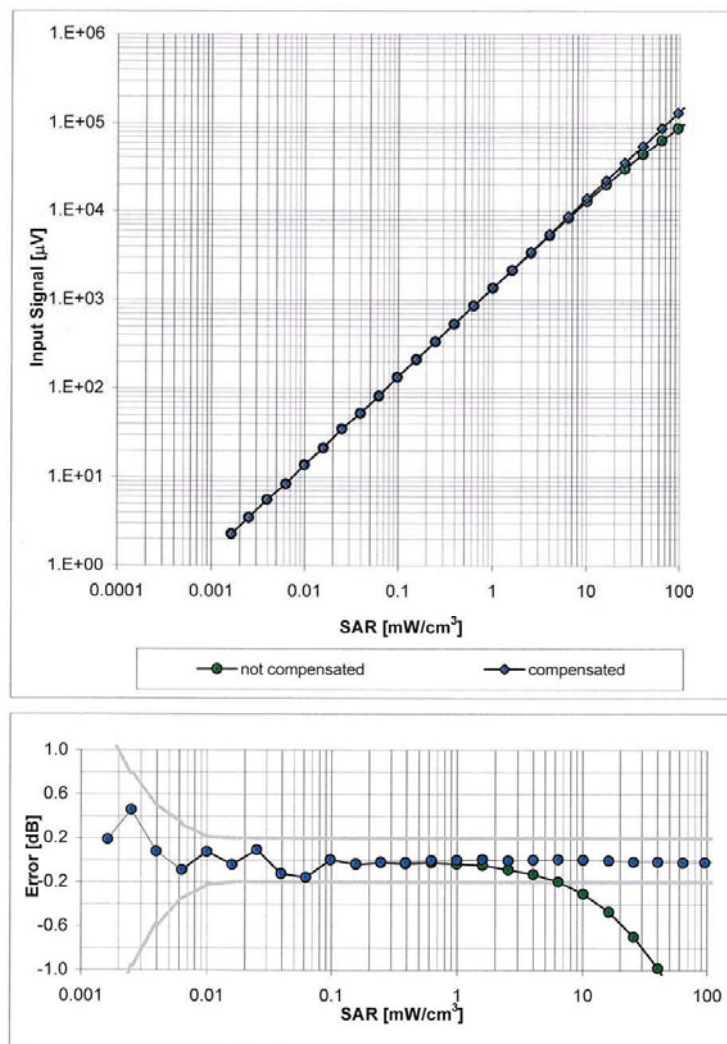
July 15, 2010

Receiving Pattern (ϕ), $\theta = 0^\circ$ Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ ($k=2$)

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Dynamic Range $f(\text{SAR}_{\text{head}})$ (Waveguide R22, $f = 1800$ MHz)

Uncertainty of Linearity Assessment: $\pm 0.6\%$ ($k=2$)